

## **VME64x Ruggedized Connectors**

- COTS and custom applications
- Designed for severe environments with high levels of shock and vibration
- Compatible with IEEE-1101.2 -1992\*
- Complies with ANSI/VITA 1.7 high current standard for VME64x
- Stackable design of high speed modules feature round pins to mate with Hypertac® contacts
- Optimized lead traces within modules provide superior performance in high speed applications
- Aluminum frames for ruggedness and conduction cooling
- Keying feature assures proper mating

	P1 / P2	PO	J1 / J2	J0				
Design criteria	IEEE-1101.2 1992							
Contact gender	Mal	e pin	Hypertac .5mm socket	Hypertac .4mm socket				
Contact termination style	Sold	er tail	Solder or press-fit					
Contact spacing	2.54 mm (5 row)	2 mm (6 row 5 + 1 shield row)	2.54 mm (5 row)	2 mm ( 6 row)				
Contact current rating	2.5 amps	1 amp	2.5 amps	1 amp				
Temperature range	minus -55 C to + 125 C							
Insulation resistance	>5000 megohm							
Insulator material	30 % glass filled LCP							
Flammability rating	94 V-O							
Pin contact material	Be	eCu						
Socket contact material			BeCu wires / brass body					
Plating mating contacts	50 micro-inch gold / 50 micro-inch nickel							
Plating contact termination	Tin lead (60- 40) / 50 micro inch nickel (MIL-P-81728)							
Suggested PCB hole diameter solder tail	1.00 mm +/- 0.05 mm after plating	0.75 mm +/- 0.05 mm after plating	1.00 mm +/- 0.05 mm after plating	0.60 mm +/- 0.05 mi after plating				
Suggested PCB hole press fit compliant tail			1.00mm +/- 0.05 after plating	0.70 mm +/- 0.05 mn after plating				



Configure and download 3D connector models or 2D drawings on this product.

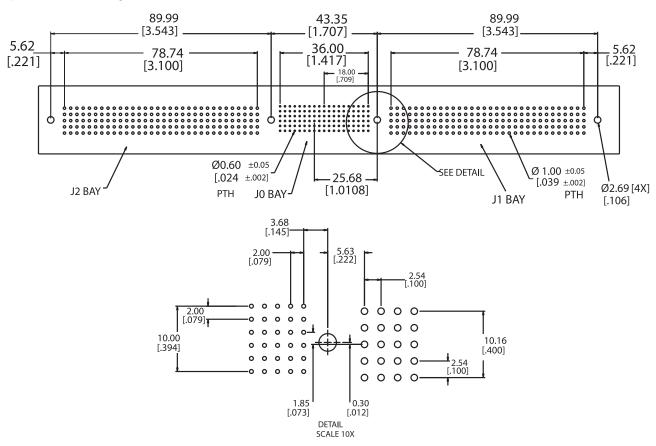
Please visit www.hypertronics.com for more details

<sup>\*</sup> Contact factory for detail



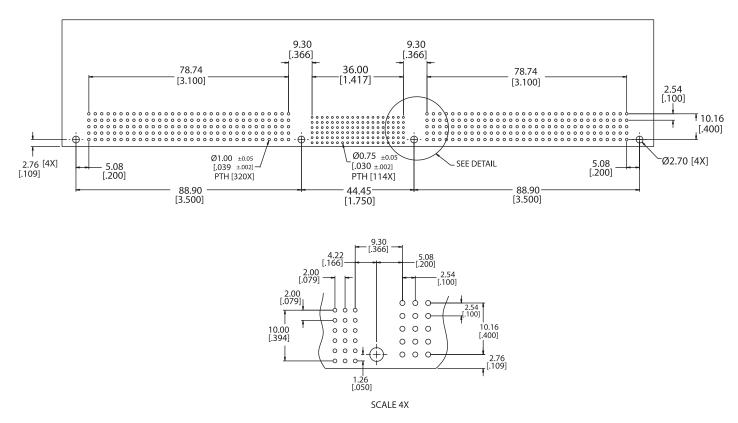
Performance Specifications							
	P1 / P2	P0	J1 / J2	J0			
CRD (contact resistance at rated curent)		4.85 milliohm average		4.85 milliohm average			
LLCR (low level contact resistance		7.20 milliohm average		7.25 milliohm average			
DWV		1000 VRMS		1000 VRMS			
Contact life (mate / demate)	> 4000 cycles						
Mating force		27.3 LBf average		27.3 LBf average			
Demating force		22.4 LBf average		22.4 LBf average			
Vibration							
Frequency		10 to 2000 to 10 HZ		10 to 2000 to 10 HZ			
Amplitude		0.05 da 15 G		0.05 da 15 G			
Duration		4.0 hours, 3 axis, 12 hour total		4.0 hours, 3 axis, 12 hour total			
Test current		100 ma		100 ma			
Sweep time		20 minutes		20 minutes			
No circuit interruptions occurred		@ 10 Nano second resolu-		@ 10 Nano second resolu-			
Mechanical Shock							
Peak value		100 G		100 G			
Duration		6 Millisecond		6 Millisecond			
Number of shocks		3 shock / 3 axis (18 total)		3 shock / 3 axis (18 total)			
No circuit interruptions occurred		@ 10 Nano second resolu-		@ 10 Nano second resolu-			

## Backplane PCB layout

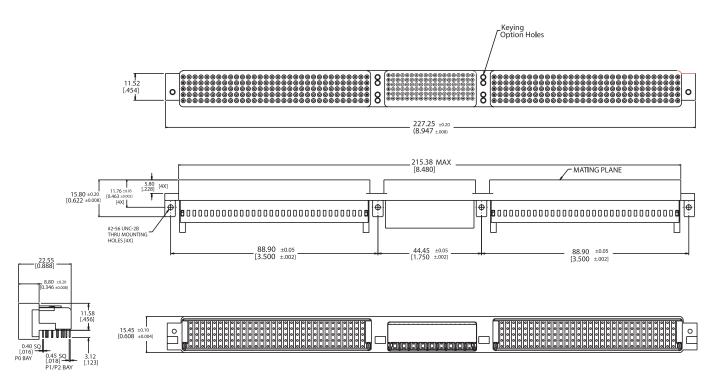




# Daughter card PCB layout

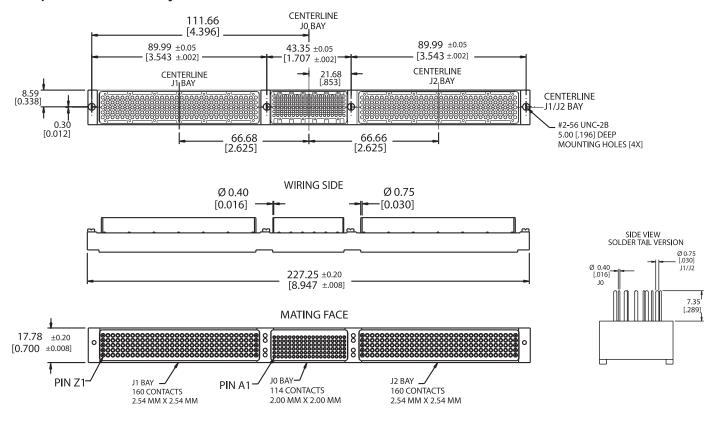


## Male assembly - KVME434MR00BH

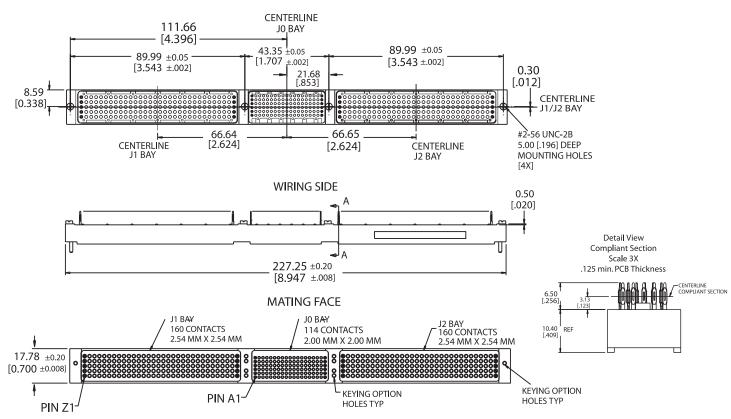




## Receptacle assembly - solder tails - KVME434FD00AH



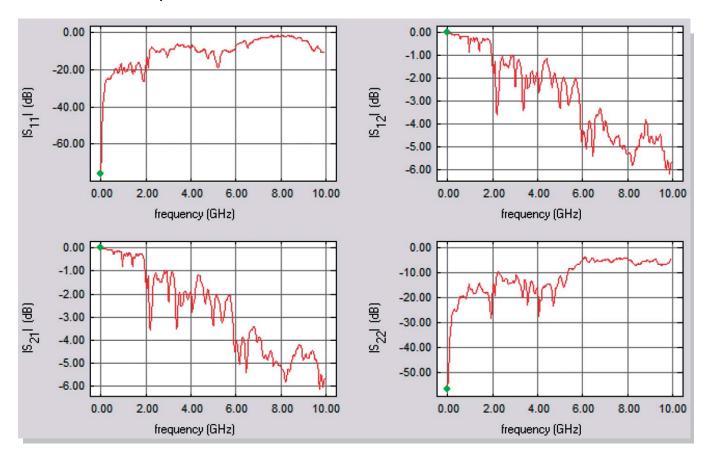
# Receptacle assembly - compliant tails - KVME434FC00AH





## J0/P0 High Speed Electrical Performance

## 1. Differential S-parameter 1, 2



## 2. Propagation Delay and Skew

Propagation delay through the intrinsic connector assembly is estimated by making a measurement on the reflected signal received on the same broadband fixture that is used to obtain the full vector scattering parameters. In these measurements, there is no inclusion of any other pin lengths other than what is within the intrinsic connector.

Parameters	Connector Row							
	а		b	(	•	d		е
Propagation Delay (ps)	68	90		112		134		156
Skew (ps)	22	22			22		22	
Maximum Data Rate 2	3.125 Gb/s							

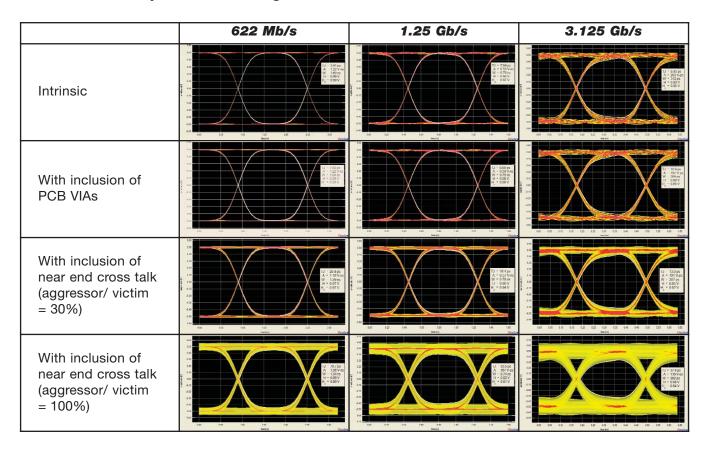
#### Notes:

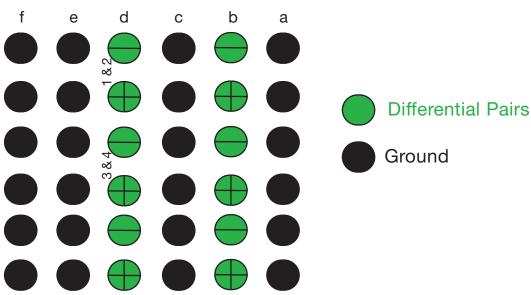
<sup>1)</sup> Pattern illustrated in the figure on next page was used in the S-parameter and cross talk measurements.

<sup>2)</sup> Please refer to the full characterization test report for details



# 3. Connector Eye-Pattern-Diagram 1, 2





#### Notes:

- 1) Pattern illustrated in the figure above was used in the S-parameter and cross talk measurements.
- 2) Please refer to the full characterization test report for details